

MOS INTEGRATED CIRCUIT $\mu PD434001AL$

4M-BIT CMOS FAST SRAM 4M-WORD BY 1-BIT

Description

The μ PD434001AL is a high speed, low power, 4,194,304 bits (4,194,304 words by 1 bit) CMOS static RAM.

Operating supply voltage is 3.3 V \pm 0.3 V.

The μ PD434001AL is packaged in 32-pin plastic SOJ and 32-pin plastic TSOP (II).

Features

• 4,194,304 words by 1 bit organization

• Fast access time: 15, 17, 20 ns (MAX.)

• Output Enable input for easy application

• Single +3.3 V power supply

Ordering Information

Part number	Package	Access time	Supply currer	nt mA (MAX.)
		ns (MAX.)	At operating	At standby
μPD434001ALLE-A15	32-pin plastic SOJ	15	130	5
μPD434001ALLE-A17	(10.16 mm (400))	17	120	
μPD434001ALLE-A20		20	110	
μPD434001ALG5-A15-7JD	32-pin plastic TSOP (II)	15	130	
μPD434001ALG5-A17-7JD	(10.16 mm (400))	17	120	
μPD434001ALG5-A20-7JD	(Normal bent)	20	110	

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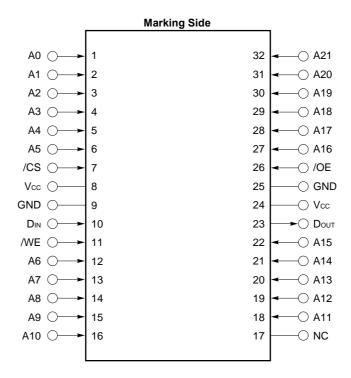


Pin Configuration

/xxx indicates active low signal.

32-pin plastic SOJ (10.16 mm (400)) [μ PD434001ALLE]

32-pin plastic TSOP (II) (10.16 mm (400)) (Normal bent) [μ PD434001ALG5-7JD]



A0 to A21: Address Inputs

DIN : Data Input

Dout : Data Output

/CS : Chip Select

/WE : Write Enable

/OE : Output Enable

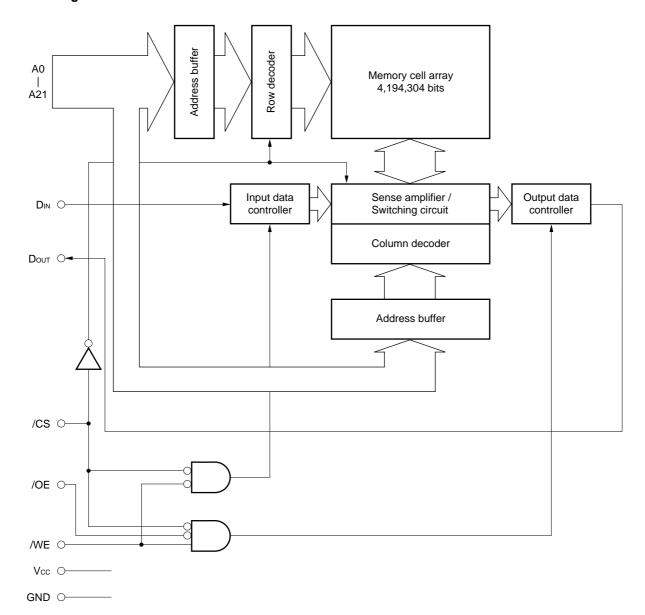
Vcc : Power supply

GND : Ground

NC : No connection

Remark Refer to **Package Drawings** for the 1-pin index mark.

Block Diagram



Truth Table

/CS	/OE	/WE	Mode	I/O	Supply current
Н	×	×	Not selected	High-Z	Isb
L	L	Н	Read	D оит	Icc
L	×	L	Write	Dın	
L	Н	Н	Output disable	High-Z	

Remark ×: Don't care



Electrical Specifications

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Supply voltage	Vcc		-0.5 ^{Note} to +4.6	V
Input / Output voltage	VT		-0.5 ^{Note} to +4.6	V
Operating ambient temperature	TA		0 to 70	°C
Storage temperature	Tstg		-55 to +125	°C

Note -2.0 V (MIN.) (pulse width : 2 ns)

Caution Exposing the device to stress above those listed in Absolute Maximum Rating could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	Vcc		3.0	3.3	3.6	٧
High level input voltage	VIH		2.2		Vcc+0.3	V
Low level input voltage	VIL		-0.3 Note		+0.8	V
Operating ambient temperature	TA		0		70	°C

Note -2.0 V (MIN.) (pulse width : 2 ns)



DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

Parameter	Symbol	Test con	MIN.	TYP.	MAX.	Unit	
Input leakage current	lu	V _{IN} = 0 V to V _{CC}		-2		+2	μΑ
Output leakage current	ILO	Vour = 0 V to Vcc,		-2		+2	μΑ
		/CS = VIH or /OE = VIH	or /WE = V _{IL}				
Operating supply current	Icc	/CS = V _{IL} ,	Cycle time : 15 ns			130	mA
		Iоит = 0 mA,	Cycle time : 17 ns			120	
		Minimum cycle time	Cycle time : 20 ns			110	
Standby supply current	IsB	/CS = VIH, VIN = VIH or	VIL			50	mA
	I _{SB1}	/CS ≥ Vcc - 0.2 V,				5	
		$V_{\text{IN}} \leq 0.2 \; V \; \text{or} \; V_{\text{IN}} \geq V_{\text{CC}} - 0.2 \; V$					
High level output voltage	Vон	Iон = -4.0 mA		2.4			V
Low level output voltage	Vol	I _{OL} = +8.0 mA				0.4	V

Remarks 1. VIN: Input voltage

Vout : Output voltage

2. These DC characteristics are in common regardless of package types.

Capacitance (T_A = 25 °C, f = 1 MHz)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	Cin	V _{IN} = 0 V			6	pF
Output capacitance	Соит	Vout = 0 V			10	pF

Remarks 1. VIN: Input voltage

Vout : Output voltage

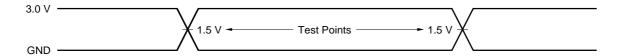
2. These parameters are periodically sampled and not 100% tested.



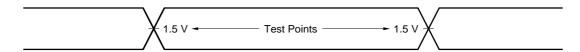
AC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

AC Test Conditions

Input Waveform (Rise and Fall Time ≤ 3 ns)

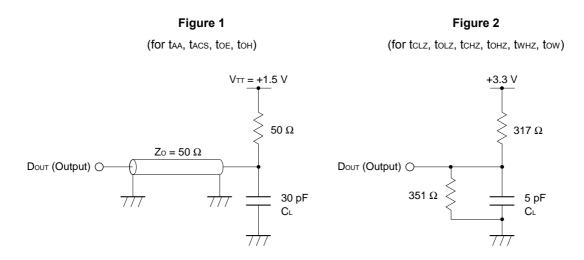


Output Waveform



Output Load

AC characteristics directed with the note should be measured with the output load shown in **Figure 1** or **Figure 2**.



Remark CL includes capacitances of the probe and jig, and stray capacitances.



Read Cycle

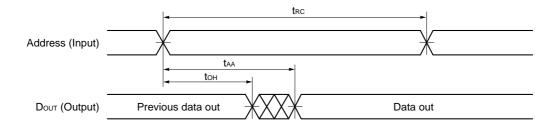
Parameter	Symbol	-A15		-A17		-A20		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	trc	15		17		20		ns	
Address access time	taa		15		17		20	ns	1
/CS access time	tacs		15		17		20	ns	
/OE access time	toe		7		8		10	ns	
Output hold from address change	tон	3		3		3		ns	
/CS to output in low impedance	tclz	3		3		3		ns	2, 3
/OE to output in low impedance	tolz	0		0		0		ns	
/CS to output in high impedance	tснz		7		8		8	ns	
/OE to output hold in high impedance	tонz		7		8		8	ns	

Notes 1. See the output load shown in Figure 1.

- 2. Transition is measured at \pm 200 mV from steady-state voltage with the output load shown in **Figure 2**.
- 3. These parameters are periodically sampled and not 100% tested.

Remark These AC characteristics are in common regardless of package types.

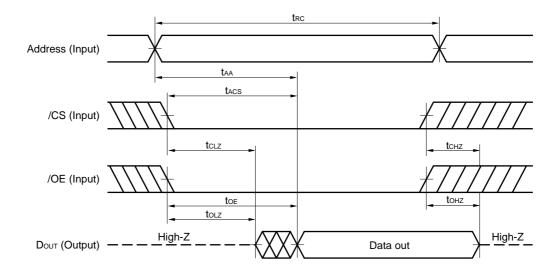
Read Cycle Timing Chart 1 (Address Access)



Remarks 1. In read cycle, /WE should be fixed to high level.

2. /CS = /OE = VIL

Read Cycle Timing Chart 2 (/CS Access)



Caution Address valid prior to or coincident with /CS low level input.

Remark In read cycle, /WE should be fixed to high level.



Write Cycle

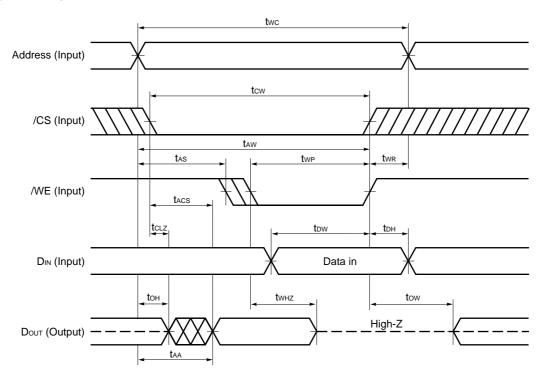
Parameter	Symbol	-A	.15	-A	17	-A	20	Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	15		17		20		ns	
/CS to end of write	tcw	10		11		12		ns	
Address valid to end of write	taw	10		11		12		ns	
Write pulse width	twp	10		11		12		ns	
Data valid to end of write	tow	7		8		9		ns	
Data hold time	tон	0		0		0		ns	
Address setup time	tas	0		0		0		ns	
Write recovery time	twr	1		1		1		ns	
/WE to output in high impedance	twnz		7		8		8	ns	1, 2
Output active from end of write	tow	3		3		3		ns	

Notes 1. Transition is measured at \pm 200 mV from steady-state voltage with the output load shown in **Figure 2**.

2. These parameters are periodically sampled and not 100% tested.

Remark These AC characteristics are in common regardless of package types.

Write Cycle Timing Chart 1 (/WE Controlled)



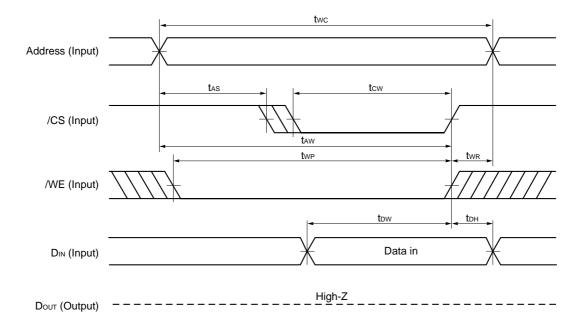
Caution /CS or /WE should be fixed to high level during address transition.

Remarks 1. Write operation is done during the overlap time of a low level /CS and a low level /WE.

- 2. During twhz, Dout pin is in the output state, therefore the input signals must not be applied to the output.
- **3.** When /WE is at low level, the Dout pin is always high impedance. When /WE is at high level, read operation is executed. Therefore /OE should be at high level to make the Dout pin high impedance.



Write Cycle Timing Chart 2 (/CS Controlled)

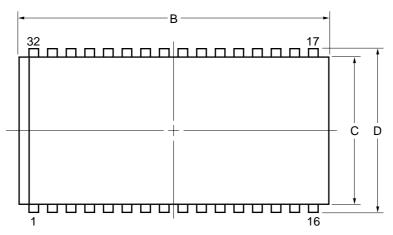


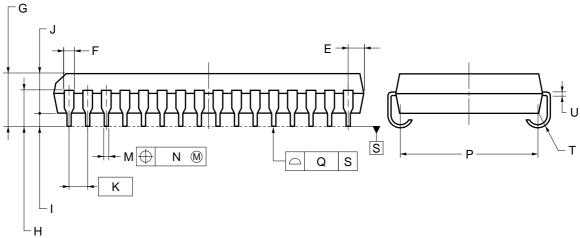
 $\label{lem:caution} \mbox{ \ensuremath{\text{CCS or /WE should be fixed to high level during address transition.}}}$

Remark Write operation is done during the overlap time of a low level /CS and a low level /WE.

Package Drawings

32-PIN PLASTIC SOJ (10.16mm (400))





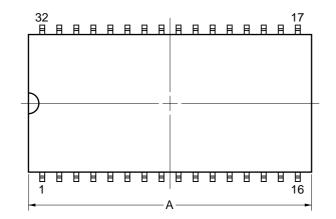
NOTE

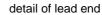
Each lead centerline is located within 0.12 mm of its true position (T.P.) at maximum material condition.

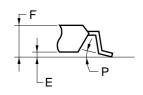
ITEM	MILLIMETERS
B	21.26±0.2
С	10.16
D	11.18±0.2
Е	1.005±0.1
F	0.74
G	3.5±0.2
Н	2.545±0.2
I	0.8 MIN.
J	2.6
K	1.27(T.P.)
М	0.40±0.10
N	0.12
Р	9.4±0.20
Q	0.1
Т	R0.85
U	$0.20^{+0.10}_{-0.05}$

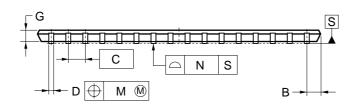
P32LE-400A-1

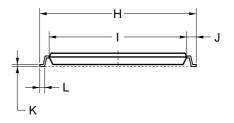
32-PIN PLASTIC TSOP (II) (10.16mm (400))











NOTE

Each lead centerline is located within 0.21 mm of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS
Α	21.17 MAX.
В	1.075 MAX.
С	1.27 (T.P.)
D	$0.42^{+0.08}_{-0.07}$
Е	0.1±0.05
F	1.2 MAX.
G	0.97
Н	11.76±0.2
I	10.16±0.1
J	0.8±0.2
K	$0.145^{+0.025}_{-0.015}$
L	0.5±0.1
М	0.21
N	0.10
Р	3°+7° -3°

S32G5-50-7JD2-1



Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the μ PD434001AL.

Types of Surface Mount Device

 μ PD434001ALLE : 32-pin plastic SOJ (10.16 mm (400))

 μ PD434001ALG5-7JD : 32-pin plastic TSOP (II) (10.16 mm (400)) (Normal bent)

NEC μ PD434001AL

[MEMO]



NOTES FOR CMOS DEVICES -

1 PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

(2) HANDLING OF THE APPLIED WAVEFORM OF INPUT PINS AND THE UNUSED INPUT PINS FOR CMOS

Note:

Input levels of CMOS devices must be fixed. CMOS devices behave differently than Bipolar or NMOS devices. If the input of a CMOS device stays in an area that is between V_{IL} (MAX.) and V_{IH} (MIN.) due to the effects of noise or some other irregularity, malfunction may result. Therefore, not only the input waveform is fixed, but also the waveform changes, it is important to use the CMOS device under AC test conditions. For unused input pins in particular, CMOS devices should not be operated in a state where nothing is connected, so input levels of CMOS devices must be fixed to high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

μPD434001AL

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